



## Characterization of Stacked 2D Materials

Two dimensional materials are heavily researched and useful devices can be built by stacking and combining multiple layers of these materials together. Optical spectroscopy measuring photoluminescence or Raman spectroscopy is widely used for characterization and analysis to determine things like stacking order, number of layers, layer orientation and more.

**Featured Paper/ Publication:** [Stacking-controllable interlayer coupling and symmetric configuration of multilayered MoS<sub>2</sub>](#), NPG Asia Materials, 2018

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**Products used:** [SpectraPro](#), [PIXIS](#)